Self Checking Circuit Optimization by means of Fault Injection Analysis: A Case Study on Reed Solomon Decoders

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Abstract—This paper shows how the use of exhaustive fault injection campaigns in conjunction with the analysis of the property of a circuit, allows to improve the efficiency of the checker of self checking circuits. Experimental results coming from fault injection campaigns on a Reed-Solomon Decoder demonstrated that by observing the occurred errors and the correspondent detection module has been possible to reduce the number of detection module, while paying a small reduction of the percentage of SEUs that can be detected.

I. INTRODUCTION

Reed-Solomon (RS) codes are widely used for protecting memories against Single Event Upsets (SEUs) because of its efficient ability to correct single upsets per coded word with reduced area and performance overhead. However, a SEU within the RS decoder can give a wrong data word even if no errors occurs during the codeword transmission. Therefore, also the RS decoder must be designed to with fault tolerance capabilities in order to realize high reliable systems.

When the analysis of SEUs is the major concern, simulation-based fault injection approaches allow early evaluation of the system dependability when only the model is available. However, considering the large complexity of such circuitry, a huge amount of CPU time may be required, thus limiting its usability to exhaustive fault tolerance capabilities evaluations. Instead, we used a partially reconfiguration based fault injection technique able to run in a fraction of the time simulation-based approaches require, supporting the execution of exhaustive fault injection campaigns.

We performed the fault injection campaign on a Reed-Solomon Decoder showing how observing the occurred errors and the correspondent detection module has been possible to reduce the number of detection modules, while paying a small reduction of the fault tolerance capabilities.

The paper is organized as follows: in Section II a description of the fault injection environment is given. In section III the RS decoder and the additional blocks used to detect faults the decoder are described, while section IV describes the set-up of the fault injection campaign and presents the obtained results. Finally, in section V the conclusions are presented.

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II. FAULT INJECTION ENVIRONMENT

The fault injection system we developed is composed by: a *host computer*; an *FPGA board* equipped with a Virtex II-Pro device, and a serial communication link to the host computer. The host computer is used for configuring the Virtex-II Pro, for the generation of a *fault location list* and to collect the results in terms of fault-effect classification.



Fig. 1. Architectural scheme of the proposed fault injection approach

The FPGA board is composed of four components interconnected by an On-chip Peripheral Bus (OPB) and its layout is depicted in Fig. 1.

- *Timing Unit (TU)*: it drives the UUT clock and reset. A port connected to the OPB Bus defines its functionality.
- Unit Under Test (UUT): it is the circuit under test. Its input and output ports are connected to the OPB while the reset and clock signals are connected to the TU.
- *ICAP*: it is the Internal Configuration Access Port provided by last generations of Xilinx FPGAs. It allows the access to all the memory elements (Flip-Flops or Latches) of the UUT to perform the partial reconfiguration.
- *PowerPC microprocessor*: it is hardwired in the FPGA device, performs the fault injection of SEUs in the UUT and communicates the fault-injection experiment results to the host computer.

The fault injection execution flow is a two-phase process composed of a preliminary phase followed by an execution phase. The flow of the preliminary phase is illustrated in Fig.



2. This phase is automatically executed by the host computer using either internal developed tools and commercial tools provided by Xilinx. During the preliminary phase the Unit Under Test is inserted within the FPGA device layout circuit description. This actions is performed by the UUT Wrapper Inserting Tool that generates a UUT wrapper inserted within the FPGA device layout description. This wrapper links the input and output ports with the OPB Bus and the clock and reset signals to the Timing Unit. The FPGA bitstream is obtained following the FPGA implementation tools chain provided by Xilinx. In particular the BITGEN tool is used to obtain the bitstream that is loaded within the FPGA configuration memory and to generate a Logic Allocation file that contains a list of all the logic resources used within the FPGA. The Fault Location List Generator reads the Logic Allocation file and generates a Fault Location List where each fault location is characterized by an identifier of the correspondent flip-flop or latches position in the FPGA.



Fig. 2. Preliminary phase of the fault injection execution flow

The execution phase is executed by the PowerPC and it consists of three parts: pre-running, campaign and fault injection results. At first, it loads within the PowerPC memory the test patterns that will be applied and initializes the UUT. Secondly, it performs a golden run of the UUT storing the Golden Output (GO) produced. The Campaign performs the fault injection of the selected number of faults (NF). The following steps are executed for the injection of each SEU:

- 1) The UUT is reseted.
- 2) A fault injection time (FT) and a fault location (FL) are randomly selected.
- The execution of the UUT is started until reached the clock cycle FT. This operation is performed by configuring a Timing Unit's counter at the FT value.
- 4) The fault location FL is read. This procedure reads directly the content of the flip-flop or latches from the configuration memory using the ICAP port.
- 5) The FPGA is partially reconfigured writing the opposite value within the content of the flip-flop or latches identified by FL. Therefore a SEU is injected in the considered fault location.
- 6) The execution of the UUT is continued until the end of the run. During the execution, it monitors the UUT output ports and comparing their value with the UUT golden outputs. It finally updates a fault classification

list (FCL) with the results obtained by the fault injection and classifying each injected SEU as silent, if the output produced by the UUT are equal to the GO; wrong answer, if a mismatch was detected.

III. DETECTION OF FAULTS IN THE RS DECODER

An RS(*n*,*k*) code [2] is defined by representing the data symbols as elements of the Galois Field $GF(2^m)$ and the overall data word is treated as a polynomial d(x) with coefficient in $GF(2^m)$. The Reed-Solomon codeword is then generated by using the generator polynomial g(x). All valid codewords are exactly divisible by q(x). The general form of q(x) is:

$$g(x) = (x + \alpha^{i})(x + \alpha^{i+1})\dots(x + \alpha^{i+2t})$$
(1)

where 2t = n - k and α is a primitive element of the field. Therefore the codeword is a polynomial c(x) of degree n - 1such as $c(x) \mod g(x) = 0$ The RS decoder is able to correct up to t errors in a received word providing as output the corrected codeword. Two main properties can be defined for a fault free RS decoder [3]:

Property 1: The decoder output is always a codeword.

Property 2: The Hamming distance between the received word and the output codeword is not greater than t.

Where the Hamming distance of two polynomials a(x) and b(x) of degree n is the number of coefficients of the same degree that are different. When the fault inside the decoder is activated, i.e. the output is different from the correct one due to the presence of the fault, two cases occur:

- 1) The decoder gives as output a non codeword, and this case can be detected by property 1.
- 2) If the output of the faulty decoder is a wrong codeword the detection of this fault is easily performed by evaluating the Hamming weight of the error polynomial e(x).

The error polynomial can be provided by the decoder as an additional output or can be evaluated by comparing the received polynomial and the provided output $\overline{c}(x)$.

This approach is completely independent by the assumed fault set and it is based only on the assumption that the fault free behavior of the decoder provides always a codeword as output. To check if properties 1 and 2 are respected some blocks can be added to the decoder. They are:

- An optional error polynomial recovery block (the shaded block in Fig. 3). This block is needed if the decoder do not provides at the output the error polynomial.
- Hamming weight counter, that checks the Hamming distance between the received word and the output word of the RS decoder.
- Codeword checker, that checks if the output data of the RS decoder form a correct codeword.

A schema of the RS decoder with the additional blocks is presented in Fig. 3.

The codeword checker block checks if c(x) is exactly divisible for the generator polynomial g(x). The syndrome





Fig. 3. Scheme of the self-checking RS decoder

calculation performs the evaluation of the received polynomial $\overline{c}(x)$ for the values of x that are roots of g(x). The received polynomial is a codeword if and only if all the computed syndromes are zero. Fig. 4 shows the implementation of the syndrome calculation block.



Fig. 4. Syndrome calculation block

These blocks allow to detect a fault inside the RS decoder without any knowledge on the implementation details of the decoder. However, is possible that some of the blocks presented in this section are not really needed for a certain implementation of the decoder. The fault injection experiments of the following section allows to identify which errors can occurs on the decoder output when a fault occurs inside it and therefore which blocks are really needed for fault detection.

IV. FAULT INJECTION EXPERIMENTS

To perform the fault injection campaign an RS(255,239) decoder with the additional blocks described in the previous section has been implemented. The syndrome calculation block is composed by 16 elementary blocks described in Fig. 4. For the fault injection campaign we call this vector $S = S_0...S_{15}$. When a fault inside the decoder is activated and property 1 is not respected albeit one byte of the syndrome vector is different from zero. The fault injection campaign has been performed injecting in two runs.

During the first run of the fault injection experiment 1,000,000 SEU are injected and the outputs of the syndrome computation block has been monitored. Monitoring these outputs, we are able to identify if the fault is activated and if the erroneous output produced by the decoder violates properties 1 or 2. If all the bytes of the syndrome vectors are equal to zero, then the erroneous output violates property 2, else it violates property one. The results achieved from the fault injection campaign report that the number of activated faults is 6,873,492 and the number of faults detected by the RS decoder is 6,873,310 which results in a fault detection of about 99.9974%. This implies that excluding the Hamming counter from the scheme of the self-checking RS decoder shown in Fig. 3 however we obtain a fault detection coverage of the RS decoder that is about 99.9974%.

In the second run 100,000 SEU are injected and the 16 bytes of the syndrome vector has been monitored to check

which bytes are able to detect an activated fault. The aim of these run is to find a subset of the syndrome elements that detect a high percentage of fault. The overall activated faults was 98174 and the fault detected by any single element of the syndrome vector S are reported in table I. The S_1 element of the syndrome vector detects most of the SEUs provoking faults. Therefore use only the block computing S_1 the system is able to detect 92% of the activated fault. Instead, using the subset composed only by S_1 and S_3 we are able to detect all the activated SEU faults. The fault injection experiments show that excluding the Hamming Distance Counter Block and using only the blocks computing S_1 and S_3 in the codeword Checker we are able to detect about 99.9974 % percentage of faults. In this case we save the logic resources needed to implement the Hamming Distance Counter Block and 14 syndrome element computation block. Instead, using also the Hamming Distance Counter Block we are able to cope 100%.

Syndrome	Detected		Syndrome	Detected	
Élement	SEUs	[%]	Élement	SEUs	[%]
S_0	7825	8	S_1	90186	92
S_2	41783	42	S_3	84994	86
S_4	27550	28	S_5	12145	12
S_6	42177	42	S_7	2114	2
S_8	1134	1	S_9	3811	4
S ₁₀	37268	38	S ₁₁	981	1
S_{12}	6534	6	S ₁₃	719	0.7
S_{14}	289	0.3	S_{15}	119	0.1

 TABLE I

 FAULT COVERAGE OF THE SYNDROME VECTOR ELEMENTS

V. CONCLUSIONS

The result presented here shown how some blocks added to the Reed Solomon decoder due to high level considerations about the decoder functionality are not really necessary to obtain an high fault detection coverage. The Hamming Counter block can be excluded from the self-checking scheme with a very small reduction of the fault tolerance capabilities. Moreover, a detailed analysis of the syndrome vector outputs allows to reduce also the blocks computing the syndrome only to a small subset, without penalty in terms of percentage of detected faults. This methodology to improve the efficiency of self-checking structures is possible only if an extensive fault injection campaign can be performed in a fast and flexible environment. The fault injection technique used in this paper is a good candidate for this task, because is able to perform injection campaigns in a fraction of the time simulation-based approaches require.

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